Search Notes

| Application/Control No. | Applicant(s)/Patent Under Reexamination |
|-------------------------|---|
| 10574131 | YANAI ET AL. |
| Examiner | Art Unit |
| David N Werner | 2621 |

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| SEARCHED | | | | |
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| Class | Subclass | Date | Examiner | |

| SEARCH NOTES | | | | | |
|--------------------------|------------|----------|--|--|--|
| Search Notes | Date | Examiner | | | |
| Espacenet | 2010.04.14 | DNW | | | |
| EAST | 2010.04.21 | DNW | | | |
| Edan Double Patent Check | 2010.04.22 | DNW | | | |

| INTERFERENCE SEARCH | | | | | |
|---------------------|----------|------|----------|--|--|
| Class | Subclass | Date | Examiner | | |
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